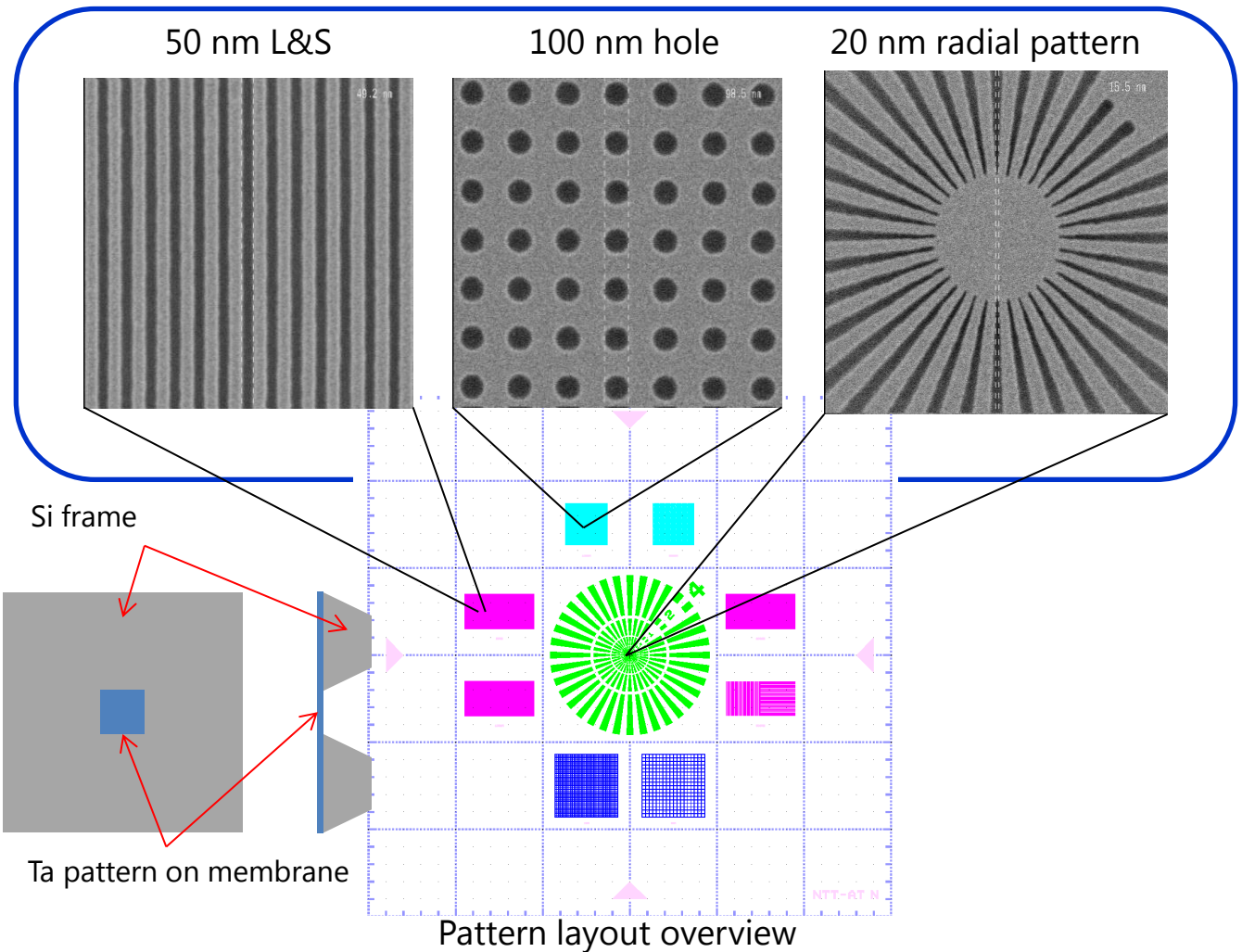


# Ultra high resolution X-ray Chart

XRESO-20 is an ultra-high resolution X-ray test chart for several applications such as;

- X-ray microscopy
- XUV/X-ray coherent imaging
- Ultra-fine X-ray inspection



- Minimum pattern: 20 nm radial pattern
- Absorber: 100 nm thick Ta
- Support membrane: 3-layer membrane (Ru/SiC/SiN)
- Frame: 10 mm x 10 mm x 0.625 mmt Si

NTT Advanced Technology Corporation

**Global Sales Section**

E-mail: [nano-sales@ml.ntt-at.co.jp](mailto:nano-sales@ml.ntt-at.co.jp)

WEB: <http://www.ntt-at.com>